
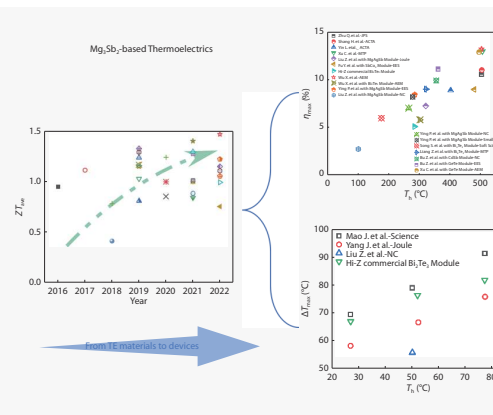


# Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectrics: materials, interfaces, and devices

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**Thermoelectric power generators enable the direct conversion between waste heat and electricity near room temperatures, providing an environmentally friendly solution toward mitigating the ever-increasing global energy issues. Over the past years, we have witnessed significant advances in Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectric conversion materials. However, the device-level efforts lag behind the materials-level works. In this mini-review, we summarize the advances in Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectrics from materials to devices. Further, we shine some light on the device-level challenge, including the design of thermoelectric interface materials, the stability issue, and the system-level full-parameter optimization. Finally, we discuss the new application scenarios exploration to inspire confidence in device-level efforts towards practical applications.**



Thermoelectric (TE) power generation devices realize the direct conversion between heat and electricity, presenting many indispensable applications in special scenarios<sup>[1–3]</sup> such as energy supply of space explores<sup>[4]</sup>, massive sensors for the internet of things (IoT)<sup>[5,6]</sup>, and waste heat recovery from power plants, car exhaust, or fossil fuels<sup>[7,8]</sup>. In addition, the cooling function of TE devices shows great potential because of the precise and fast micro-zone temperature control<sup>[9,10]</sup>, especially for the thermal management of microchips<sup>[11,12]</sup>. Very recently, high-efficiency TE devices assembled with state-of-the-art TE materials are frequently emerged in the prestigious news, such as PbTe<sup>[13]</sup>, half-Heusler<sup>[14]</sup>, GeTe<sup>[15]</sup>, SnSe<sup>[16]</sup>, Cu<sub>2</sub>Se<sup>[17]</sup>, AgSbTe<sub>2</sub><sup>[2]</sup>, Mg<sub>3</sub>Sb<sub>2</sub><sup>[9]</sup>, and so on. In particular, eco-friendly, and cost-effective Mg<sub>3</sub>Sb<sub>2</sub>-based TE devices show extraordinary popularity and desirable superiority at a middle-low temperature range<sup>[9,10,18–20]</sup>, which are expected to replace N-type Bi<sub>2</sub>Te<sub>3</sub><sup>[21,22]</sup> that is the exclusive TE material presently applied in the commercial market. However, the most mature Bi<sub>2</sub>Te<sub>3</sub> and its alloys thermoelectrics are still dominant for the widely accepted solid-state or limited power generation application in the commercial market<sup>[21,23]</sup>. Recently, Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectric ma-

terials attract exclusive attention in either the middle-low temperature range or near room temperatures application for the rich abundance of Mg as compared with the rare element Te in the Bi<sub>2</sub>Te<sub>3</sub><sup>[9,10,18–20]</sup>. Compared with quick and significant progress in the Mg<sub>3</sub>Sb<sub>2</sub>-based TE materials, the Mg<sub>3</sub>Sb<sub>2</sub>-based devices progress hardly due to the challenges in electrode interface design and device assembling<sup>[24,25]</sup>. As a result, there is still a yawning gap between theoretical and experimental conversion efficiency ( $\eta$ ), and output power density ( $\omega$ ) for the reported Mg<sub>3</sub>Sb<sub>2</sub>-based TE devices<sup>[18–20,26–38]</sup>.

Before moving to the main content, we would like to clarify the terminology of the key component materials of a TE device based on our previous work<sup>[24]</sup>. For example, there are anode materials, cathode materials, electrolytes, and separators for the ionic battery<sup>[39]</sup>. The assembling of a TE device also requires similar key component materials, such as (a) thermoelectric conversion materials (TECMs) that realize the energy conversion, (b) thermoelectric interface materials (TEIMs) that play an important role to maintain the reliable and efficient transport of heat and electricity between electrode strip and TECMs, (c) protection material, usually used to prevent the evaporation of the TECM and/or thermal insulation, (d) housing materials, providing structural support and electrical insulation. The aforementioned four types of materials just follow the four quadrants of a two-dimension space expanded by electrical conductivity ( $\sigma$ ) in the vertical axis and thermal conductivity ( $\kappa$ ) in the horizontal axis. The classic n and p-type materials fall in the second quadrant, which requires a high  $\sigma$  and low  $\kappa$ , referred to as TECMs. While the metallization layer materials require a high  $\sigma$  and high  $\kappa$ , setting at the first quad-

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rant, referenced as TEIMs [24].

In this mini-review, we focus on the recent new progresses from the  $Mg_3Sb_2$ -based TE materials to devices. Further, we discuss the device-level challenges including the TEIMs design, the stability optimization, and the system-level full-parameter optimization. In the outlook, we also look ahead to the new application scenarios exploration towards practical applications.

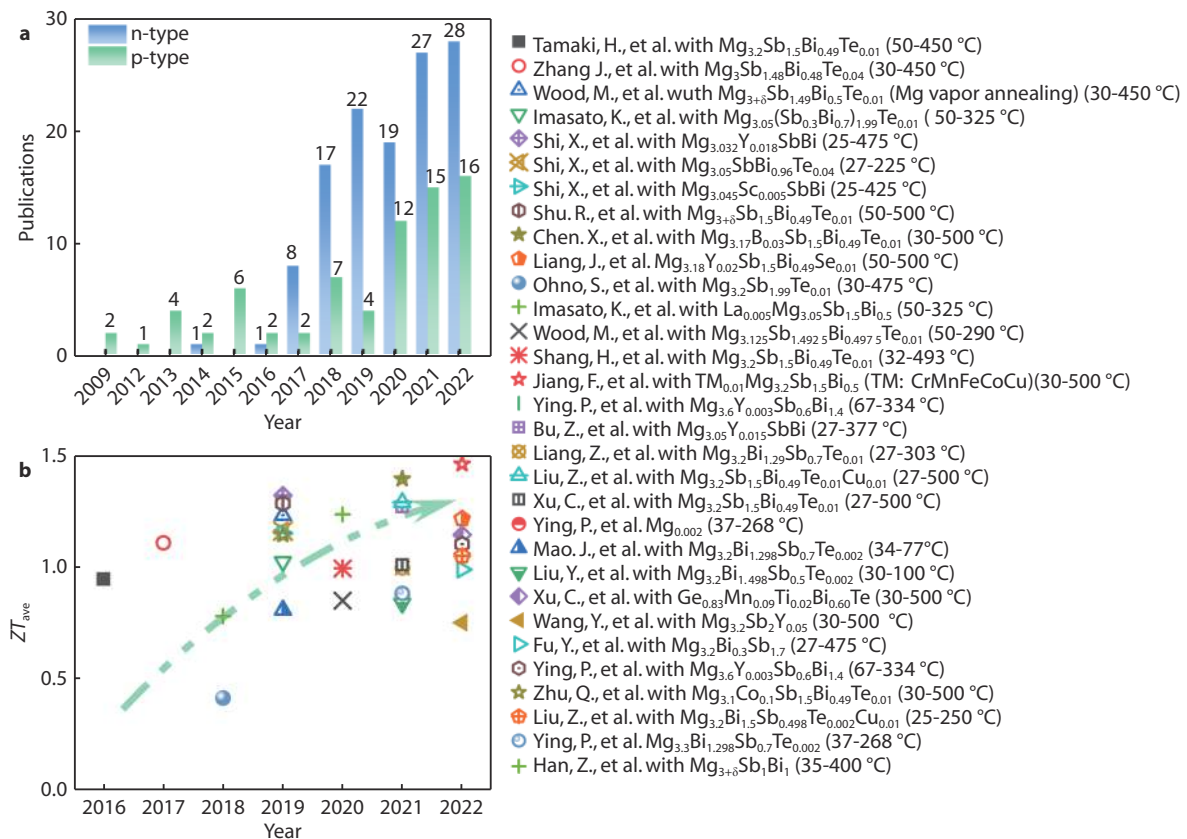
## Progress in $Mg_3Sb_2$ -based TECMs

$Mg_3Sb_2$  has a VB group element (Sb and Bi, respectively). Sb has 3-valence electrons in  $Mg_3Sb_2$ , which could be considered an inverse structure of  $Bi_2Te_3$ . The crystalline structures of  $Mg_3Sb_2$  and  $Bi_2Te_3$  in trigonal laminar structure, where Te atoms at 3a site (0, 0, 0) are donated  $Te^1$  while Te atoms at 6c site (0, 0, 0.79030(5)) are  $Te^2$ . For each atomic layer in both compounds, atoms are stacked in a hexagonal pattern, and these two compounds share the same layer-to-layer stacking sequence, and this is the intrinsic reason for its low lattice thermal conductivity. Furthermore, the high valley degeneracy and relatively low-energy-closed point with the CBM point make  $Mg_3Sb_2$  family the promising TECM [40].

$Mg_3Sb_2$ -based TECMs were originally reported that could make the transition between p-type and n-type, being n-type on the side with excess Mg and p-type on the side with excessive Sb in 1956 [57,58]. However, it regains our sight since the discovery of the excellent n-type TE properties in 2016 [42,59]. Subsequently, Snyder *et al.* [43,50], Pei *et al.* [44,49,60],

Liu *et al.* [46], and Ren *et al.* [9] nearly simultaneously reported exciting TE performance near room temperature (below 300 °C) in 2018 and 2019, showing the great potential of  $Mg_3Sb_2$ -based TECMs for the substitution of commercial n-type  $Bi_2Te_3$ . In addition, Liu *et al.* [54], Sui *et al.* [56] and Chen *et al.* [45] successfully realize a high  $ZT$  of over 1.8 at 500 °C, allowing the high average  $ZT_{ave}$   $Mg_3Sb_2$ -based TECMs and thus benefiting the TE devices over a wide temperature range (Fig. 1).

However, the stability of  $Mg_3Sb_2$ -based TECMs remains a great concern in practical applications. Many investigators exposed that the underlying reason causing the degradation was the Mg loss [51,52,59,61]. Fortunately, efforts like the cation or interstitial site doping [52,53,60], hot deformation [10], Mg vapor annealing [43], and depositing protective coating [28,62] could alleviate Mg evaporation and improve the stability of  $Mg_3Sb_2$ -based TECMs. For instance, Liu *et al.* showed that interstitial Mn [46] or Multi-elements transition metals (CrMnFeCoCu) [54] dopant could suppress the Mg-vacancy formation, thereby improving the thermal stability. Snyder *et al.* [53] and Pei *et al.* [60] reported that Yb, Y, and La doping on the cation site could stably control the carrier concentration. Further, Zhao *et al.* [10] exhibited a stable cooling module via a post-hot deformation process to stabilize the Mg vacancies concentration at ambient temperature. Very recently, Ren *et al.* [28] and Liu *et al.* [62] reported that spraying BN and Mg-Mn alloy coating could also suppress the volatilization of Mg and then achieve high thermal stability. Further, electrical and chemical stability are highly concerned. The high current density seems to have little effect on the TE properties [30,62], but the



**Fig. 1** **a** Publications and **b**  $ZT_{ave}$  vs. Year. Literature results [9,18,20,26-28,30-34,36,38,41-56] are included for comparison.

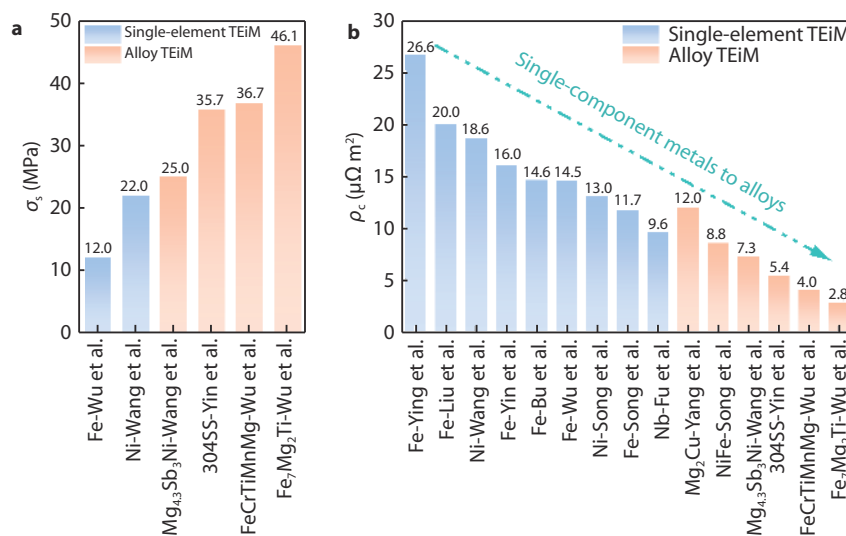
lifetime of  $\text{Mg}_3\text{Sb}_2$ -based TECMs is more sensitive to moisture other than the considered oxygen<sup>[63]</sup>. Note that there is no specific parameter to quantify stability at present, and a general criterion to evaluate the stability is worth being defined in the future. Furthermore, the real service environment of a TE device is more complex; thus, we hope that multiple strategies mentioned above working together or creating new solutions to improve stability need to be developed in the future.

## Progress in TEiMs for $\text{Mg}_3\text{Sb}_2$ -based TECMs

Although the  $\text{Mg}_3\text{Sb}_2$ -based TECMs are booming and flourishing, the advances in relative devices are slowed and obstructed by the challenges at TEiM/TECM interfaces<sup>[24,25]</sup>. The  $ZT_{\text{ave}}$  relationship between TECMs and TE devices could bridge by the formula<sup>[64]</sup>,  $ZT_D = \frac{L}{L + 2\rho_c\sigma} ZT_{\text{ave}}$ , where  $ZT_D$  and  $ZT_{\text{ave}}$  are the effective value of TECM  $ZT_{\text{ave}}$ .  $\sigma$ ,  $\rho_c$ ,  $L$ , and  $A$  are the electrical conductivity of TECMs, specific contact resistivity, length, and cross-sectional area of the TE Leg, respectively. For a commercial TE device ( $L \sim 2$  mm and  $\sigma \sim 10^5$  S  $\text{cm}^{-1}$ ), the  $\rho_c$  must be  $< 10 \mu\Omega \text{ cm}^{-2}$  and bonding strength ( $\sigma_s$ ) should be  $> 30$  MPa, thereby obtaining  $> 95\%$  output performance and robust mechanical stability<sup>[24]</sup>. Generally, the fabrication of TE devices is based on soldering or brazing<sup>[65]</sup> to pursue high  $\sigma_s$  and low  $\rho_c$  then allow reliable and high output performance<sup>[66]</sup>. Unfortunately, most TECMs exhibit poor weldability owing to their semiconductor behavior<sup>[25]</sup>; thus the TEiMs, or named metallization layers are inevitably required to realize a reliable bonding between TECMs and electrodes<sup>[67]</sup>. Generally, a high  $\sigma_s$  requires necessary diffusion; however, it might also result in an increased  $\rho_c$ . It is difficult to balance the high  $\sigma_s$  and low  $\rho_c$  for a single-element TEiM; thus, the synergetic achievement in low  $\rho_c$  and high  $\sigma_s$  is a great challenge for the whole TE community because of the mutual exclusivity.

Interface contact problems have been extensively studied in classically commercial  $\text{Bi}_2\text{Te}_3$  devices<sup>[68,69]</sup>, but have not re-

ceived sufficient attention in  $\text{Mg}_3\text{Sb}_2$ -based TE devices. Recently, researchers have attempted to use Fe<sup>[9,18,19,27,28,32]</sup>, Ni<sup>[9,33]</sup>, and Nb<sup>[34]</sup> as the TEiM layer for  $\text{Mg}_3\text{Sb}_2$ -based TE power generation devices. For instance, Ren *et al.*<sup>[31]</sup>, Pei *et al.*<sup>[30]</sup>, and Schierning *et al.*<sup>[18]</sup> respectively reported that the  $\rho_c$  of  $\text{Fe}/\text{Mg}_3(\text{Sb}, \text{Bi})_2$  interfaces are approximately 2.5, 14.6, and  $26.6 \mu\Omega \text{ cm}^2$  (Fig. 2). However, the  $\rho_c$  of  $\text{Fe}/\text{Mg}_3(\text{Sb}, \text{Bi})_2$  interfaces could increase to  $60 \mu\Omega \text{ cm}^2$  after the power generation service<sup>[19,29,30]</sup>, suggesting that interface diffusion or reaction occurs. Similarly, Fu *et al.* used Nb as the TEiM for n-type  $\text{Mg}_3\text{Sb}_2$  and achieved a low  $\rho_c$  of  $9.7 \mu\Omega \text{ cm}^2$  together with an increased  $\rho_c$  of  $26 \mu\Omega \text{ cm}^2$  after the high-temperature service, thereby creating a significant gap between the experimental and theoretical power generation performances<sup>[34]</sup>. Some alloying TEiMs for n-type  $\text{Mg}_3\text{Sb}_2$ -based TECMs, including 304 stainless steel (304SS)<sup>[29]</sup>,  $\text{Mg}_2\text{Cu}$ <sup>[10]</sup>,  $\text{Fe}_{90}\text{Sb}_{10}$ <sup>[70]</sup>, NiFe, NiCr, NiCrFe<sup>[35]</sup>,  $\text{Mg}_{3.4}\text{Sb}_3\text{Ni}$ <sup>[36]</sup>,  $\text{Fe}_7\text{Mg}_2(\text{Cr}, \text{Ti})$ <sup>[37]</sup>, and  $\text{FeCrTiMnMg}$ <sup>[62]</sup> were subsequently reported to show lower  $\rho_c$  values (Fig. 2). For example, Ren *et al.* reported that the  $\text{NiFe}/\text{Mg}_3\text{Bi}_{1.5}\text{Sb}_{0.5}$  contact exhibits a highly stable  $\rho_c$  of  $13 \mu\Omega \text{ cm}^2$  after aging for over 2100 h<sup>[35]</sup>. In addition, we have suggested an alloying approach to design the TEiM rather than using available alloys, which has already been verified as an effective technique with some necessary characteristics, including high bonding propensity, coefficient of thermal expansion matching, diffusion passivation, and dopant inactivation<sup>[24]</sup>. As a result, Fe was selected from 15 elements as the matrix element, considering the criteria of high  $\sigma_s$  and low  $\rho_c$ , and further designed two ternary alloys ( $\text{Fe}_7\text{Mg}_2\text{Cr}$  and  $\text{Fe}_7\text{Mg}_2\text{Ti}$ ) with  $\sigma_s > 40$  MPa and  $\rho_c < 5 \mu\Omega \text{ cm}^2$ <sup>37</sup>. Multi-elements TEiM ( $\text{FeCrTiMnMg}$ ) has been further applied for the  $\text{Mg}_3\text{Sb}_{1.5}\text{Bi}_{0.5}$  TE devices according to the above alloy screening principles, allowing the excellent interface stability and visually proven by in-situ TEM technique<sup>[62]</sup>. Of note, in the  $\text{Mg}_3\text{Sb}_2$ -based TECMs family, the higher the carrier concentration, the lower the  $\rho_c$ <sup>[71]</sup>. Therefore, the TECMs with different carrier concentrations should adapt to different TEiMs, and more attention ought to be devoted to the contacts investigation.

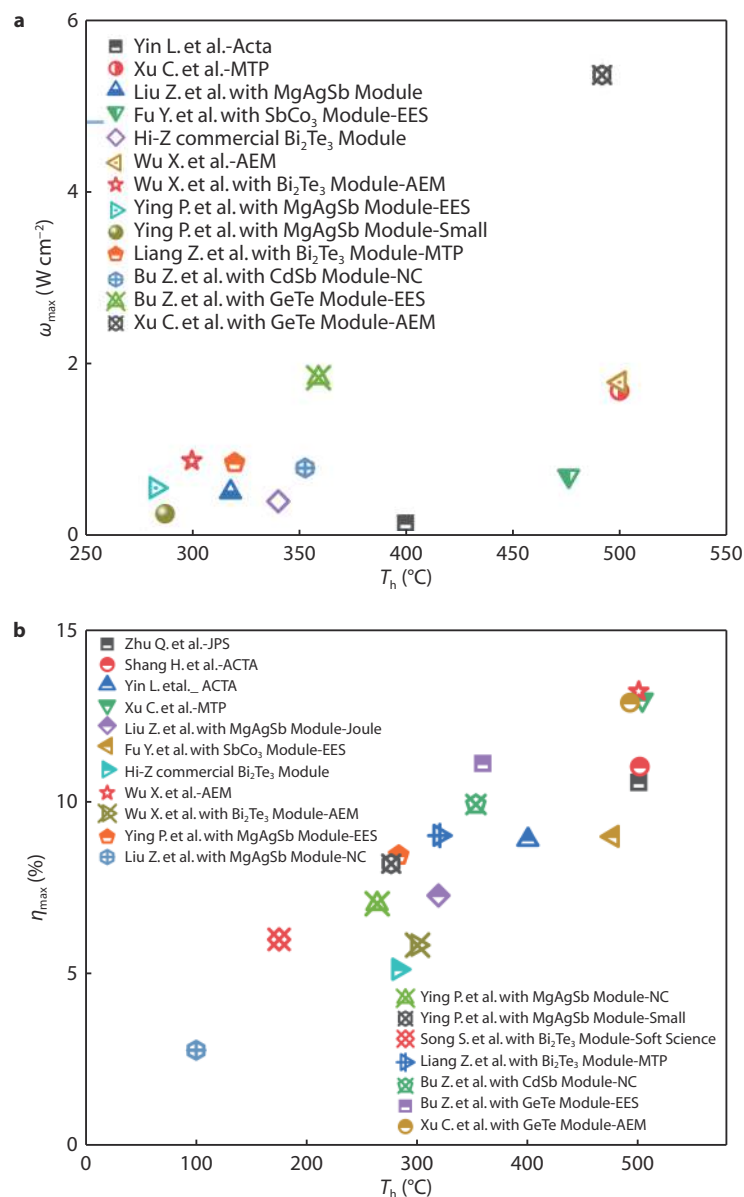


**Fig. 2** a The initial values of  $\sigma_s$  and b  $\rho_c$  of the TEiM/TECM interfaces near room temperatures. Literature results<sup>[10, 18, 20, 29, 30, 34-37, 62]</sup> are included for comparison.<sup>[58]</sup> Copyright 2022, Wiley-VCH.

## Progress in Mg<sub>3</sub>Sb<sub>2</sub>-based TE devices

For the past two or three years, state-of-the-art Mg<sub>3</sub>Sb<sub>2</sub>-based TE devices are originally emerging, exhibiting outstanding power generation performance in the temperature range from RT to 500 °C (Fig. 3). Early, Ren *et al.* reported an Mg<sub>3</sub>Sb<sub>2</sub>-based single-leg TE device with a high  $\eta$  of 10.6% when hot side temperature ( $T_h$ ) reached 500 °C in 2019<sup>[27]</sup>. Subsequently, Zhang *et al.* applied 304SS as TEiM instead of single-element Fe and obtained an excellent single-leg device with a  $\eta$  of 9% at a  $T_h$  of 400 °C in 2020<sup>[29]</sup>. Further development begins in 2021; TE module devices with p-type Bi<sub>2</sub>Te<sub>3</sub><sup>[9,10,31,35,48,62]</sup>, MgAgSb<sup>[18,20,32,38,72]</sup>, CdSb<sup>[19]</sup>, GeTe<sup>[26,30]</sup>, and SKD<sup>[34]</sup> were reported sequentially and yielded great success. During this flourishing period, the key factors considering practice application are gradually concerned, including scalable fabrication<sup>[33]</sup>, electrical stability<sup>[30,62]</sup>, chemical stability<sup>[63]</sup>, and thermal stability<sup>[28,34–36,38,62]</sup>.

We have mentioned above that reliable TE devices are contributed by optimizing TEcMs<sup>[10,38]</sup>, designing TEiMs<sup>[29,34–36,62]</sup>, and applying protective coating<sup>[28,62]</sup>. Typically, He *et al.* successfully fabricated reliable TE devices by higher temperature sintering and Mg heavy overcompensation, and the robust modules are proved via thermal shock testing over 30,000 times when  $T_h$  varied between 50 and 227 °C<sup>[38]</sup>. Wang *et al.* used Nb as the TEiM for n-type Mg<sub>3</sub>Sb<sub>2</sub> and achieve a  $\eta$  of 9% in the Mg<sub>3</sub>Sb<sub>2</sub>-CoSb<sub>3</sub> modules, showing excellent thermal stability at a  $T_h$  of 500 °C<sup>[34]</sup>. The high  $\omega_{\max}$  of about 5.35 W cm<sup>-2</sup> was achieved in the Mg<sub>3</sub>Sb<sub>2</sub>-GeTe device owing to the excellent power factor of TEcM and the low  $\rho_c$  of the TE devices<sup>[26]</sup>. Note that the  $\omega_{\max}$  is unified by using the envelope area of devices. Very recently, Liu *et al.* have reported a multi-element TEiM (FeCrTiMnMg) and functional protective coating (Mg-Mn-based alloy) to de-



**Fig. 3**  $T_h$ -dependent **a**  $\omega_{\max}$  and **b**  $\eta_{\max}$ . Literature results are included for comparison<sup>[18-20,26-38,48,62,72-74]</sup>.

crease the chemical potential gradient, reduce the saturated vapor pressure, and increase the diffusion activation energy barrier, thereby realizing a high  $\omega_{\max}$  and  $\eta_{\max}$  of 1.7 W cm<sup>-2</sup> and 13% at a  $T_h$  of 500 °C; moreover, the optimized device exhibited excellent stability within 100 h and  $T_h$  cycled between 200–400 °C over 200 times with a TE performance degradation < 10 %<sup>[62]</sup>. In addition, employing device structure design and segmenting TE material with different Sb content are also progressed, thereby achieving outstanding device performance<sup>[18,26,31,72]</sup>. Further, new application models such as TE cooling<sup>[9,10,20,38]</sup> (Fig. 4) and flexible power generation devices<sup>[48]</sup> are pushed forward, which is likely to bring Mg<sub>3</sub>Sb<sub>2</sub>-based TE devices investigation into the era of explosion.

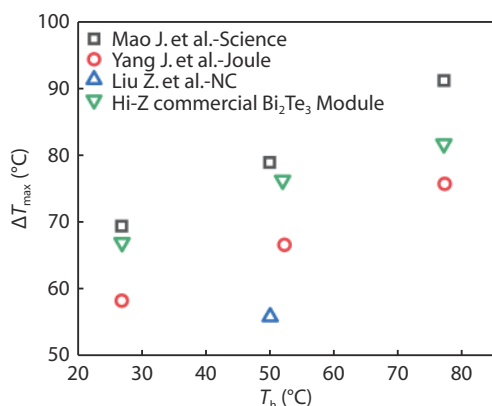


Fig. 4  $T_h$ -dependent  $\Delta T_{\max}$ . Literature results are included for comparison<sup>[9,10,20,73]</sup>.

## Summary and Outlook

The TE community has put great efforts into Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectrics, however, the challenges at the device level remain critical and must be overcome before industrial implementation. Seeking high ZT is always a primary orientation, but the stability of TECMs especially at elevated temperatures should not be ignored. In addition to the synthesis process and composition optimization, new ways to improve stability without sacrificing TE properties deserves our consideration. The mechanical properties are vitally important, especially for micro-TE devices. Li *et al.* optimized the mechanical properties through the nano-SiC-dispersed<sup>[75]</sup> and proposed the microelectromechanical technology fabricating micro-TE devices<sup>[76]</sup>, broadening the exclusive dominance for Bi<sub>2</sub>Te<sub>3</sub>-based thermoelectrics. Therefore, optimizing the mechanical properties of Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectrics is absolutely an attractive aspect to broaden the new application scenario.

Designing TEIMs is a key to fully realizing a high device-level performance. Alloying appears to be the trend for rapidly and effectively screening TEIMs; however, more advanced TEIMs still require more scholars to devote. For real TE application systems, collaborative full-size optimization and device life prediction are all indispensable domains, which still need to be well established in Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectrics.

Exploring new application scenarios is also a keyway to

promoting the development of Mg<sub>3</sub>Sb<sub>2</sub>-based thermoelectrics, including but not limited to power generation, cooling, sensing, and thermal management. Energy supply for massive IoT sensors<sup>[6]</sup> and wearable devices<sup>[48,77]</sup>, human temperature perception system of electronic skin<sup>[78]</sup>, micro cold storage for Covid-19 vaccine<sup>[79,80]</sup>, temperature control for laser diodes, infrared detectors, charge-coupled devices, and computer chips<sup>[81]</sup>, thermal cycling for DNA synthesizer<sup>[12]</sup>, etc. have been initially developed. More importantly, exploring innovative applications requires our cross-collaboration in different research fields, thereby creating a green and beautiful lifestyle using thermoelectrics.

## CONFLICT OF INTEREST

The authors declare no conflict of interest.

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## AUTHOR CONTRIBUTIONS

Xinzhi Wu: writing—original draft. Jian Huang, Zihan Zhou, Zhijia Han, Huan Li, Yupeng Wang, and Zhu Kang: revision. Weishu Liu: revision, supervision.

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## Biographies



**Xinzhi Wu**, he is a PhD candidate in southern university of science and technology, majoring in Materials Science and Engineering. His research interest focuses on thermoelectric materials and related devices.



**Liu Weishu**, his research topic is room-temperature thermoelectric materials and devices. He proposed a general material parameter  $B^*$  for searching new thermoelectric materials and discovered the selective enhancement effect of ionic transport in the gelatin-based ionic thermoelectric materials. He also made an exclusive contribution to wearable thermoelectric devices. He has published over 130 papers in high reputation journals, including *Science*, *PNAS*, *Nat. Comm.*, *Energy Environ. Sci.*, *Adv. Mater.* etc., and has total citations over 10000 times and H-index of 52. He has been awarded the “Tencent XPlorer Prize 2019”.